# 1 H2GCROC2/2A: architectural overview

The overall block diagram is described as per below. Compared to HGCROCV1, the "one channel" undergoes no functional change, as well as the trigger path. The memory is changed from SRAM to DRAM to save power and the electrical and physical interfaces are now be the final ones. An important modification is the final pinout, going from wire bonding to C4 bump bonding. The chip handles 72 channels + 4 channels for common mode subtraction + 2 special calibration channels.



## 1.1 Analog front-end

The front-end may be divided in three main sub-parts:

The preamplifier part which converts the input charge coming from the SiPM to an output voltage. It must provide the first amplification of the signal with the best noise performance. The preamp stage is mad of a current conveyor with a variable gain and a charge variable charge preamp. The conveyor gives the ability to tune the preamp input voltage via a channel wise DAC.

In the linear part of the amplifier, the feedback capacitors and feedback resistors provide the gain and the shape of the output signal which is send to the shaper. From the saturation and above, the feedback discriminator triggers and provides the charge measurement by using the "Time Over Threshold" technique (TOT). Another discriminator allows to give the timing information.

The preamplifier can be calibrated by injecting a voltage step through two channel-wise selectable capacitors (0.5pF and 8pF).

- The shaper part is composed of three stages: a Sallen-Key filter, a RC<sup>2</sup> filter and a unity gain amplifier to drive the ADC. The shaping time can be adjusted over +/- 20% to compensate for process variations and ensure out of time pileup below 20%.
- The two discriminators providing the TOT and TOA (Time of Arrival) pulses, each one sent to a dedicated TDC.



In order to accommodate the C4 bump bonding pattern, the layout was entirely redone in order to fit in 120 µm height and avoid sensitive analog electronics below the bumps. Four channels fit between two rows of pads and the slow control, common to 4 channels, is placed below the pads.



In addition to the 72 readout channels, there are 4 channels for common mode subtraction and 2 channels for MIP calibration. The common mode channels are similar to the regular channels except they stop at the ADC (there are not TDCs). They do not enter the trigger path but are read out in the data path.

In the following sections, more details are given for each blocks.

#### *1.1.1 Preamplifier*

The preamplifier is DC coupled to the input and provides three outputs:

 Out\_pa connected to the **shaper** and the **TOT discriminator**. Its DC operating point is the same than the preamplifier input (160 - 200 mV).

Out pa time connected by default to the **TOA discriminator**. Its DC operating point is around outpa + Vgs ( $\sim$  500 mV).

A 6b-DAC is connected channel wise to the preamplifier input to tune the DC level at the input and adjust the SiPM bias voltage.

A current 6b-DAC is connected channel wise also to compensate the current in the preamp feedback resistor.

The purpose of the preamplifier is to convert the input charge to a voltage output with the best signalto-noise ratio and a gain adapted to the MIP signal. It must also provide a "short" signal duration to mitigate the Out-of-Time pileup effect at the shaper output. To meet all these requirements, the gain and the time constant must be adjustable **(these parameters are global, not channel-wise)**. In the table below, all the possibility are described:



The following plot shows the preamplifier response to a 10 fC input charge for different choice of gain. The feedback resistor is adjusted so that the Rf\*Cf product is constant and so the "duration" of the signal. As can be seen in Fig. , an undershoot appears for the highest preamp gain.



In the table below, all the parameters concerning the preamplifier are described.

*Preamplifier parameters*



Since the preamplifier converts an input charge to an output voltage, its behaviour over the entire charge dynamic must be well known and characterized. That can be divided in three steps:

- The linear mode: the preamplifier provides an output amplitude proportional to the input charge. It is able to provide linear amplitude over ~300mV dynamic range<sup>1</sup> (see red curves in the following plot). The ADC is used to measure the charge in this region which is named ADC range.
- The non-linear mode: this mode occurs in-between the linear and the saturated modes when the preamplifier is no longer linear but not still fully saturated. It is in this region that the TOT threshold has to be set in order to optimize the ADC range linearity. The preamplifier non-

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linear mode leads to the non-linearity of the TOT low range, but the pile-up limitation is expected to be the best in this region (see violet and blue curves in the following plot and red curves in the next). The non-linear mode occurs for an output amplitude between 500 and 600mV.

The saturated mode: it occurs for an output amplitude above 600mV. In this region, the preamplifier pulse width is proportional to the input charge and so well suited to use the Timeover-Threshold technics. The drawback is the undershoot of the preamplifier signal leading to incorrect charge measurement in the next bunch crossing. The undershoot is due to the fact that in saturation the preamplifier is in open loop and consequently slower to recover its normal behaviour.

#### *1.1.2 Shapers*

The shaper is divided in three stages:

- A Sallen-Key (S-K) shaper
- An Amplifier
- Then a buffer to drive the ADC

Two global 10b-DACs allow the user to adjust the DC levels, and so the pedestal of the shaper outputs. One additional local 5b-DAC allows to reduce the dispersion of the pedestals per channel.



## *Shaper parameters*



### *1.1.3 Discriminators*

There are two discriminators per channel, one for the TOT measurement, the other for the TOA.

The TOT discriminator is connected on the "out pa output" of the preamplifier (160 – 200 mV). The TOA discriminator is connected to the "out\_pa\_time" output of the preamplifier ( $\sim$  500 mV). Two global 10b-DACs allow the user to adjust the thresholds of the discriminators and two local 5b-DACs allow to reduce the dispersion per channel.

There are two external trigger inputs available; typically, in the case when the user wants to calibrate the TOT and TOA, he can send a trigger for the TOA discriminator and the other for the TOT discriminator. He can also send a trigger for a channel, and the other for a neighbouring channel.

The two discriminators outputs can be masked per channel as well.

Regarding the TOT discriminator, when it is triggered (output at 0), it enables a constant current source which discharges the preamplifier so that the duration of the preamp signal is proportional to the input charge. This current source can be adjusted over 6 bits in order to adjust the width of the TOT (nominal specification is 200ns for 10 pC).

The two discriminators outputs can be probed and looked at on a scope.



## *Discriminators parameters*



## 1.2 Mixed-signal blocks

### *1.2.1 10 bits ADC and Align Buffer*

Both chips, HGCROC2 and HGCROC2A, embed two versions of ADC, designed by AGH in Krakow. For channels 36 to 71, there is a silicon-proven ADC with vrefm reference voltage tied to ground. For channels 0 to 35, a new version of the ADC was submitted with a dedicated vrefm set at 100 mV (nominal).



The 10 bits data provided by the ADC are sent to an Align Buffer to align them to the TOT and TOA data. Indeed, the TDCs providing the TOT measurement introduce a latency due to the duration of the TOT itself (this latency is tuneable in the TDCs). The ADC + Align Buffer have a fixed latency of 11 bunch crossings: sampling at BC=1, ADC data available at BC=2, data at the Align Buffer ouputs at BC=11 (see next chronogram).



*ADC parameters*



**The Align Buffer also performs the pedestal subtraction.**

**The user can choose to force ADC data to 0 when the TOT pulse is at 1 (Clr\_ADC="1"), otherwise it provides the actual ADC values.**

**As after a TOT the shaper returns to the pedestal after a given time, the user can also choose to force ADC data to 0 for two next bunch crossing after the end of the TOT pulse (Clr\_ShaperTail="1").**

The following plot shows the linearity and the INL expressed in % of the ADC range in the default parameters setting.



#### *1.2.2 TOT and TOA TDCs*

One TDC block handles the TOA and TOT measurements. It was designed by the CEA IRFU group in Saclay. The two following tables give the specifications respectively for the TOA and the TOT.







The schematic below gives an overview of the TDC circuitry.

More detailed explanations about circuit, functionality and configuration can be found in dedicated documentation:

- **HGCROC\_TOA\_TOT\_PLL\_SPECIFICATIONS.pdf** describing the specifications of all parts designed by IRFU
- **SC\_TDC\_PLL\_blocs.docx** where the user will find descriptions, default values of all slow control parameters of the two TDCs and the PLL
- **PLL and multi-channel TDC for HGCROCv2 TestPhase preparation.pdf** where is described the tests to be performed for characterizing the PLL and the TDCs;



## *TDCs parameters*









The following plot shows the digitized TOA time walk.



The following plot shows the TOT linearity and the INL expressed in % of the dynamic range.



## 1.3 Digital blocks

The main specifications of the digital part of the ASIC are described in the table below.



#### HGCROC2 integrates 72 channels to readout

- 192 channels sensor with a 64-ch configuration
- 432 channels sensor with a 72-ch configuration



The document **HGROCv2\_LinkSpecs\_Guide.pdf** details the data path and the trigger path.

#### *1.3.1 Data path*

All the data coming from the ADC and the two TDCs are continuously memorized into a circular memory based on a DRAM architecture. The circular memory is 512 length and only L1-triggered data are read out. Two output differential port send out the data at 1.28 Gbps.

Special channels, common mode and calibration channels, provide only the ADC data.

The figure below describes the functionality of the data path.



The ADC and the TOA data are over 10 bits each and the TOT in 12 bits. All these data are stored at 40 MHz continuously into the DRAM; there is the possibility to compress the TOT data to 10 bits. The DRAM memory is controlled as a circular memory. After receiving a L1 trigger, a readout of the selected BX data is activated (the offset of the L1 trigger is configurable by slow control).



An idle packet is continuously sent out when no L1 trigger is activated. This Idle packet is configurable by slow control. The data format is described in the figure below and is composed of 1376 bits.



The 32b header is as follow:



With BxCpt the number of the Bunch Crossing counter and WADD the column address of the L1 triggered event.

The 32b data of channels are described in the table below.



### *1.3.2 Trigger path*

The data processing for the trigger path is composed as per below:

- Charge linearization over ADC/TOT range
- Sum of 4 or 9 channels depending on the sensor
- Charge compression to fit the bandwidth

The parameters involved in the charge linearization are:

ADC pedestal to be subtracted

- TOT pedestal to be subtracted
- ADC threshold to force TOT to 0 if below
- TOT threshold to define the non-linear part of the TOT
- Multiplication factor with a LSB ratio between TOT and ADC



The value of the Multiplication factor allows to linearize the ADC range and the TOT range; it is coded over 5 bits in order to cope with the three typical gains:

- 31 for the 80fC ADC range
- 15.6 for the 160fC ADC range
- 7.8 for the 320fC ADC range

(The default slow control value is 25 for a theoretical 100fC ADC range.)

The schematic below describes the principle of the trigger sums for low density and high density sensors.



After the linearization, the selection between the sum by 4 (TC4) or 9 (TC9) is done by the ASIC parameter "SelTC4".

The table below gives an overview of the trigger path output format.





#### *1.3.3 Digital parameters*

The table below gives all the parameters of the digital block for the data and trigger paths, thus there are two of them in the chip as there are two digital blocks for the both sides of the chip.



SelTCA, namely Select Trigger Cell of 4 channels, allows the user to select the sum mode: set to 1 to sum 4 channels, otherwise sum by 9.



#### *1.3.4 Startup Sequence*

After each hard reset or "ReSync" commands, the startup sequence is initiated:

- It guarantees a minimum of 256 32b words of Idle packet for all serial links (Trigger and DAQ)
- 28 bits set by slow control (default 11 00 ---- 11 00) + 4b header set by bx0 (1010 else 1001)



The Daq link will complete current L1 transfer in case of ReSync command.

### 1.4 Interfaces blocks

The document **HGCROCv2\_configure\_command\_Guide.pdf** details the two following sections.

#### *1.4.1 Fast command*

All the ASICs receive, through LpGBT, a fast command link (data + clock):

- 1 link is composed by a clock at 320 MHz and a data "T1" link
- 8 bits command format: '110 xxxx 1'
- Synchronisation code: 110 (this code does not appear elsewhere in bitstream)
- Serial commands transmitted MSB first at 320 Mb/s

In HGCROC2/2A and H2GCROC2/2A, a minimum set of commands are decoded and used: Idle, CalibrationReq, L1A + clock synchronization (others are only decoded).



The available commands are described in the following table:



#### *1.4.2 I2C*

I2C protocol is used to access ASIC parameters. Main features are given in the table below:



The I2C circuits of the chip has 8 internal registers whose the use is described in the table below:



To cope with the large number of parameters, extended addressing is used:

- 512 sub\_address can be addressed (B15, B14 not used and have to be set to 0)
- Each sub\_address has max 32 configuration parameters
- Extended addressing realized through 2 direct access registers: R0 and R1



The frame of the I2C protocol is always the same:



To write, set R/W bit to 0 and to read set R/W to 1.

For instance, to set a specific 8b word of the chip, the users has to write into the R0 register then R1 register to select the good parameters register address, and then write the data into the R2 register.



The user can also write into consecutive parameters register addresses: rather to write the parameters into the R2 register, he has to write successively into the R3 register.







### *1.4.3 Output E-links*

The output differential links are composed of a serializer and a driver compatible with the LpGBT protocol. The serializer converts parallel 32 bits words at 40 MHz to a serial train of bits send out at 1280 MHz.



In the table below, the electrical specifications of the driver are given.



The termination load resistor must be placed outside the chip.

## 1.5 Ancillary blocks

### *1.5.1 PLL and clocks distribution*

The main specifications of the PLL are described in the following table:



The clock distribution is described in the figure below.



The shaper signal needs to be sampled to its maximum in order to optimize the signal-to-noise ratio; to do that the phase of the 40MHz sampling clock needs to be adjustable. The phase is adjusted by steps of  $\sim$  1.5 ns (640 MHz period).

#### *1.5.2 Bandgap and voltage references*

See the document **datasheet BGP 130nm.pdf** for detailed information about the bandgap.

Four global 10 bits DACs provide voltage references for the analog part: the two discriminator thresholds, the inverted and non-inverted references for the shaper. As the circuit is symmetrical, there are two bandgaps and two sets of voltage references with DACs for the two right and left subparts.

The voltage references are fabricated from the bandgap, the 10b DAC and the preamplifier output of a common mode channel (channels CM<1> and CM<3>) so that the chip is not sensitive to the temperature (see Design Review report for more detailed information).

#### *1.5.3 Calibration circuit*

The charge injection can be made by injecting a voltage step externally or with an internal 11b-DAC as described in the figure below.



Assuming the 11b-DAC provides a voltage up to around 1 V, the user may set 0.5pF or/and 8pF injection capacitances in the chosen channels, to study the  $0 - 0.5$  pC range, the  $0 - 8$  pC range or, by setting the both capacitances, the  $0 - 8.5$  pC range. To correctly calibrate the ADC/TOT behavior, it is important to have an overlap between the available charge ranges.

The ctest node comes from an external pad and allows the user both to use an external pulser rather than the calibration DAC and also to calibrate the calibration 11b-DAC.

# 2 Packaging, I/Os and powering scheme

The chip pinout has been defined by the hexaboard constraints [Tommaso et al.] and the BGA package that will be used to house the chips, as shown in figure below.



The two figures below show the left view and the right view of the die. Can be noticed the common column 25 in both figures.



The figure below shows the top view of the BGA map as can be seen on the board.



# 2.1 <u>Pin list</u>









### 2.2 Short description of some particulars signals/modes

The pin Rstb is the global reset of the chip. This signal is active at 0, it performs the reset of the entire digital part (counters, address pointers), and also of the Master TDC and TDCs, and ADC**. It does not execute the reset of the I2C parameters.**

### *2.2.1 Fast commands*

The fast commands link is composed by two differential links:

- Clk320\_(p)(n): Clock at 320 MHz
- Fcmd\_(p)(n): fast command as described in section 1.4.1 Fast commands

### *2.2.2 I2C protocol*

The I2C link is composed of four pins

- SDA: I2C data link
- SCL: I2C clock link
- I2C rstb: reset of the I2C parameters
- Error: Open drain output (a resistor must be routed outside the chip)

#### *2.2.3 Debug and Backup*

In the case where Fast Command or PLL do not work properly, the user can configure external clocks and signals to go forward the characterization of the chip.

#### *2.2.3.1 The fast commands and/or 40MHz clock cannot be extracted from the Fcmd link*

The available fast commands in HGCROC2 chip are described in the section "1.4.1 Fast Command". And the parameters allowing to by-pass them are described in "3.7 Top Sub-block I2C parameters".

If the fast commands cannot be extracted from the Fcmd link, the user can use specific pins to send the commands:

- Strobe ext in place of the Cmd Calib command
- L1 ext in place of the Cmd Trigger command
- OrbitSync\_ext in place of the Cmd\_Orbit command
- ReSync\_ext in place of the Cmd\_Sync command

If the 40MHz clock cannot be extracted from the fast command link, the user can set the pin Sel\_CK\_ext to 0 and use a clock coming from the Clk40  $(p)(n)$  pins. In this debug mode, the fast commands are not provided by the dedicated circuit but by the external pins.

#### *2.2.3.2 The PLL does not work properly*

In this case, the user can provide a 640MHz clock via the Clk320 link and by using specific parameters, described in section "3.7 Top Sub-block I2C parameters", he can provide all necessary clocks (640, 160, 40 MHz).

#### *2.2.4 Calibration*

Both in the left and right parts, the Vref\_\* pins output the reference voltage of the analog front-end. These outputs allows the users to calibrate with an external ADC these references and monitor them as well. In the same way, the value of the bandgap can be tuned and monitored.

The nominal way to calibrate the chip is by sending a Cmd Calib command via the fast command link. This command send a STROBE signal which performs the injection of the charge given by  $CALIB<sub>DAC</sub>*RangeCap (see parameters available in the section preamplifier). But the user has also the$ ability to inject externally a voltage pulse by using a pulser. In this case it has to choose the IN\_Ctest\_R/L pins (the pin should be externally 50Ω adapted). The IN\_Ctest\_R/L pins allows also the user to calibrate the CALIB $_{\text{DAC}}$ , in this case the pin must be in high impedance.

Several pins allows to probe internal signals:

- Probe\_PA\_R/L: probe the preamplifier output
- Probe\_DC1\_R/L and Probe\_DC3\_R/L: probe bias nodes, see parameters of register #8 in "3.4 Reference Voltage I2C parameters"
	- *Probe 1 (2.5V PAD):*
	- o Vbi\_pa: "0001", 500mV default value
	- o Vbm\_pa: "0010", 630mV default value
- o Vbm2\_pa: "0011", 420mV default value
- o Vbm3\_pa: "0100", 200mV default value
- o Vbo\_pa: "0101", 400mV default value
- o Vb\_inputdac: "0110", 460mV default value
- o Vb\_conv: "0111", 800mV default value
- o Vb dac trim: "1000", 800mV default value
	- *Probe3 (1.2V PAD):*
- $\circ$  Vb suiv2 pa : "1001"
- $\circ$  Vb suiv1 pa: "1010"
- o Vbi discri tot: : "1011"
- o Probe\_Vref\_pa: : "1100"
- o Vcp: : "1101"
- o VD\_FTDC\_N\_EXT: : "1110"
- o VD\_CTDC\_N\_EXT: : "1111"
- Probe\_DC2\_R/L: probe bias nodes, see parameters of register #8 in "3.4 Reference Voltage I2C parameters"
	- *Probe 2 (1.2V):*
	- o Vbi\_discri\_toa: "0001", 360mV default value
	- o Vcasc\_discri\_toa: "0010", 1V default value
	- o Vbm1\_discri\_toa: "0011", 810mV default value
	- o Vbm2 discri\_toa: "0100", 800mV default value
	- o Vbo discri toa: "0101", 550mV default value
	- o EXT\_REF\_TDC: "0110",
	- o NC: "0111"
	- o NC : "1000"
	- o NC : "1001"
	- o Vbm\_discri\_tot: "1010"
	- o Vbo discri tot: "1011"
	- o Probe\_Vref\_time: "1100"
	- o Vcn: "1101"
	- o VD\_FTDC\_P\_EXT: "1110",
	- o VD\_CTDC\_P\_EXT: "1111",
- Probe Toa R/L: probe the TOA discriminator output
- Probe\_Tot\_R/L: probe the TOT discriminator output
- ADCP\_R/L: probe the non\_inverted shaper output; allows also to calibrate the ADCs by applying a DC voltage
- ADCN\_R/L: probe the inverted shaper output; allows also to calibrate the ADCs by applying a DC voltage
- Trig\_R/L and Trig2\_R/L: allows to applying an external pulse to the discriminators, TOT and/or TOA, in order to calibrate the TDCs.
- VrefP\_ADC\_R/L: positive reference voltage of the ADC
- VrefN\_ADC\_R/L: negative reference voltage of the ADC. On the half (ch 36-71), connected to Vcm\_ADC as negative reference on this side is the ADC ground.
- Vcm\_ADC\_R/L: common mode reference of the ADC

# ASIC parameters

As described in section **1.4.2 I2C,** the I2C circuit has 8 internal registers; the four first are dedicated to write/read the slow-control parameters. Registers 4, 5 and 6 are direct access registers and the register 7 is a status register in read-only mode.



In the tables below, the content of the direct access registers is described.









### 3.1 I2C Addressing

The four first I2C registers, R0-3, allow to define the address and the data to write or read into the internal 8 bits registers distributed into the chip sub-parts. R0 and R1 define the address of internal 8 bits registers. R2 defines the data to write into the chosen internal 8 bits register. R3 allows the user to access successive register address.

The chip, from I2C protocol point of view, is divided in sub-blocks containing maximum 32 registers each. In consequence, the address in 16 bits (given in R0 and R1) is composed of two sub-address:

- The 11 MSB bits code the address of the sub-block
- The 5 LSB bits code the address of the register of the sub-block

The table below gives the address, the name and a short description of all the sub-blocks.







# 3.2 "Channel-wise" I2C parameters

































# 3.3 "Global analog" I2C parameters



































# 3.4 "Reference Voltage" I2C parameters















Non Inverter shaper global reference







# 3.5 "Master TDC" I2C parameters







































See Annexe A for more details about TDCs parameters.

# 3.6 "Digital half" I2C parameters





































# 3.7 "Top sub-block" I2C parameters



















